

Olivier Thomas

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232
papers

3,239
citations

31
h-index

45
g-index

243
ext. papers

3,524
ext. citations

3.9
avg, IF

4.81
L-index

#	Paper	IF	Citations
232	First-principles study of the structural, electronic, vibrational, and elastic properties of orthorhombic NiSi. <i>Physical Review B</i> , 2009 , 79,	3.3	159
231	Interplay between anisotropic strain relaxation and uniaxial interface magnetic anisotropy in epitaxial Fe films on (001) GaAs. <i>Physical Review Letters</i> , 2003 , 90, 017205	7.4	122
230	Molybdenum disilicide: Crystal growth, thermal expansion and resistivity. <i>Solid State Communications</i> , 1985 , 55, 629-632	1.6	111
229	Electrical and optical properties of silicide single crystals and thin films. <i>Materials Science and Engineering Reports</i> , 1993 , 9, 141-200		88
228	Inversion of the diffraction pattern from an inhomogeneously strained crystal using an iterative algorithm. <i>Physical Review B</i> , 2007 , 76,	3.3	65
227	Some titanium germanium and silicon compounds: Reaction and properties. <i>Journal of Materials Research</i> , 1990 , 5, 1453-1462	2.5	63
226	Effect of Co, Pt, and Au additions on the stability and epitaxy of NiSi ₂ films on (111)Si. <i>Journal of Applied Physics</i> , 1998 , 84, 2583-2590	2.5	62
225	Reaction of titanium with germanium and silicon-germanium alloys. <i>Applied Physics Letters</i> , 1989 , 54, 228-230	3.4	62
224	The diffusion of elements implanted in films of cobalt disilicide. <i>Journal of Applied Physics</i> , 1988 , 64, 2973-2980	5.7	57
223	Inversion Domain Boundaries in GaN Wires Revealed by Coherent Bragg Imaging. <i>ACS Nano</i> , 2015 , 9, 9210-6	16.7	54
222	Metallurgical reinvestigation of rare earth silicides. <i>Applied Surface Science</i> , 1989 , 38, 156-161	6.7	52
221	Diffusion of Sb, Ga, Ge, and (As) in TiSi ₂ . <i>Journal of Applied Physics</i> , 1988 , 63, 5335-5345	2.5	46
220	Formation of Ni silicide from Ni(Au) films on (111)Si. <i>Journal of Applied Physics</i> , 1996 , 79, 4078	2.5	42
219	First-principles study of nickel-silicides ordered phases. <i>Journal of Alloys and Compounds</i> , 2011 , 509, 2639-2644	3.7	41
218	Interdependence of elastic strain and segregation in metallic multilayers: An x-ray diffraction study of (111) Au/Ni multilayers. <i>Journal of Applied Physics</i> , 2000 , 87, 1172-1181	2.5	41
217	Analysis of the electrical resistivity of Ti, Mo, Ta, and W monocrystalline disilicides. <i>Journal of Applied Physics</i> , 1989 , 65, 1584-1590	2.5	40
216	Nucleation and growth in the reaction of titanium with germanium and some silicon-germanium alloys. <i>Applied Surface Science</i> , 1989 , 38, 27-36	6.7	40

215	Limits of validity of the crystallite group method in stress determination of thin film structures. <i>Thin Solid Films</i> , 1998 , 319, 9-15	2.2	39
214	Progress of in situ synchrotron X-ray diffraction studies on the mechanical behavior of materials at small scales. <i>Progress in Materials Science</i> , 2018 , 94, 384-434	42.2	38
213	Strain field in silicon on insulator lines using high resolution x-ray diffraction. <i>Applied Physics Letters</i> , 2007 , 90, 111914	3.4	38
212	Fast pole figure acquisition using area detectors at the DiffAbs beamline Synchrotron SOLEIL. <i>Journal of Applied Crystallography</i> , 2013 , 46, 1842-1853	3.8	37
211	Dislocation storage in single slip-oriented Cu micro-tensile samples: new insights via X-ray microdiffraction. <i>Philosophical Magazine</i> , 2011 , 91, 1256-1264	1.6	37
210	Combined synchrotron x-ray diffraction and wafer curvature measurements during NiBi reactive film formation. <i>Applied Physics Letters</i> , 2005 , 87, 041904	3.4	36
209	Raman spectra of TiN/AlN superlattices. <i>Thin Solid Films</i> , 2000 , 380, 252-255	2.2	36
208	Thin-film growth and compositional effects in YBa ₂ Cu ₃ O _{7-x} layers prepared by metalorganic chemical vapor deposition. <i>Journal of Applied Physics</i> , 1993 , 74, 4631-4642	2.5	34
207	Stress, porosity measurements and corrosion behaviour of AlN films deposited on steel substrates. <i>Thin Solid Films</i> , 2000 , 359, 221-227	2.2	33
206	3D Imaging of a Dislocation Loop at the Onset of Plasticity in an Indented Nanocrystal. <i>Nano Letters</i> , 2017 , 17, 6696-6701	11.5	32
205	Interfacial structure in (111) Au:Ni multilayers investigated by anomalous x-ray diffraction. <i>Physical Review B</i> , 2001 , 64,	3.3	32
204	Mechanisms for success or failure of diffusion barriers between aluminum and silicon. <i>Journal of Vacuum Science and Technology A: Vacuum, Surfaces and Films</i> , 1989 , 7, 875-880	2.9	32
203	bending of an Au nanowire monitored by micro Laue diffraction. <i>Journal of Applied Crystallography</i> , 2015 , 48, 291-296	3.8	31
202	Expected and unexpected plastic behavior at the micron scale: An in situ Laue tensile study. <i>Acta Materialia</i> , 2012 , 60, 1252-1258	8.4	31
201	Applicability of an iterative inversion algorithm to the diffraction patterns from inhomogeneously strained crystals. <i>Physical Review B</i> , 2008 , 78,	3.3	31
200	Stresses arising from a solid state reaction between palladium films and Si(001) investigated by in situ combined x-ray diffraction and curvature measurements. <i>Journal of Applied Physics</i> , 2003 , 94, 1584-1591	2.5	31
199	Asymptotic behaviour of stress establishment in thin films. <i>Surface Science</i> , 2000 , 465, L764-L770	1.8	30
198	Stresses during Silicide Formation: A Review. <i>Defect and Diffusion Forum</i> , 1996 , 129-130, 137-150	0.7	30

197	Optical properties of WSi ₂ and MoSi ₂ single crystals as measured by spectroscopic ellipsometry and reflectometry. <i>Solid State Communications</i> , 1987 , 62, 455-459	1.6	30
196	Nickel silicide encroachment formation and characterization. <i>Microelectronic Engineering</i> , 2010 , 87, 245-248	2.3	29
195	Low temperature specific heat of VSi ₂ , NbSi ₂ , and TaSi ₂ . <i>Journal of Low Temperature Physics</i> , 1993 , 92, 335-351	1.3	29
194	Resistivity and magnetoresistance of high-purity monocrystalline MoSi ₂ . <i>Journal of Physics F: Metal Physics</i> , 1986 , 16, 1745-1752		28
193	Scanning force microscope for in situ nanofocused X-ray diffraction studies. <i>Journal of Synchrotron Radiation</i> , 2014 , 21, 1128-33	2.4	27
192	Chemical vapor deposition of silicon-germanium heterostructures. <i>Journal of Crystal Growth</i> , 2000 , 216, 171-184	1.6	27
191	Mechanical characterization of low-k and barrier dielectric thin films. <i>Microelectronic Engineering</i> , 2005 , 82, 368-373	2.5	26
190	Controlling dislocation nucleation-mediated plasticity in nanostructures via surface modification. <i>Acta Materialia</i> , 2019 , 166, 572-586	8.4	26
189	Vibrational response of free standing single copper nanowire through transient reflectivity microscopy. <i>Journal of Applied Physics</i> , 2013 , 114, 193509	2.5	25
188	Segregation and strain relaxation in Au/Ni multilayers: An in situ experiment. <i>Applied Physics Letters</i> , 1999 , 75, 914-916	3.4	25
187	Electronic properties of CoSi ₂ studied by reflectivity and spectroscopic ellipsometry. <i>Solid State Communications</i> , 1986 , 60, 923-926	1.6	25
186	Direct Observation of Gigahertz Coherent Guided Acoustic Phonons in Free-Standing Single Copper Nanowires. <i>Journal of Physical Chemistry Letters</i> , 2014 , 5, 4100-4	6.4	24
185	Methodology for studying strain inhomogeneities in polycrystalline thin films during in situ thermal loading using coherent x-ray diffraction. <i>New Journal of Physics</i> , 2010 , 12, 035018	2.9	24
184	Oxidation of titanium, manganese, iron, and niobium silicides: Marker experiments. <i>Journal of Applied Physics</i> , 1990 , 68, 5133-5139	2.5	24
183	Evolution of Crystal Structure During the Initial Stages of ZnO Atomic Layer Deposition. <i>Chemistry of Materials</i> , 2016 , 28, 592-600	9.6	23
182	In situ three-dimensional reciprocal-space mapping during mechanical deformation. <i>Journal of Synchrotron Radiation</i> , 2012 , 19, 688-94	2.4	23
181	Some transport properties of single crystals of group Va transition metal disilicides. <i>Applied Surface Science</i> , 1991 , 53, 247-253	6.7	23
180	Superconductivity in TaSi ₂ single crystals. <i>Physical Review B</i> , 1992 , 45, 4803-4806	3.3	22

179	Concentration and strain fields inside a Ag/Au core-shell nanowire studied by coherent X-ray diffraction. <i>Nano Letters</i> , 2013 , 13, 1883-9	11.5	21
178	In situ study of stress evolution during the reaction of a nickel film with a silicon substrate. <i>Microelectronic Engineering</i> , 2004 , 76, 318-323	2.5	21
177	Spatiotemporal Imaging of the Acoustic Field Emitted by a Single Copper Nanowire. <i>Nano Letters</i> , 2016 , 16, 6592-6598	11.5	21
176	Retrieval of the atomic displacements in the crystal from the coherent X-ray diffraction pattern. <i>Journal of Synchrotron Radiation</i> , 2014 , 21, 774-83	2.4	20
175	Crystal growth, characterization and resistivity measurements of TiSi ₂ single crystals. <i>Journal of the Less Common Metals</i> , 1987 , 136, 175-182		20
174	Influence of Si substrate orientation on stress development in Pd silicide films grown by solid-state reaction. <i>Applied Physics Letters</i> , 2003 , 83, 1334-1336	3.4	19
173	Low-temperature intrinsic plasticity in silicon at small scales. <i>Acta Materialia</i> , 2018 , 161, 54-60	8.4	19
172	Diffusion of boron, phosphorus, and arsenic implanted in thin films of cobalt disilicide. <i>Journal of Vacuum Science and Technology A: Vacuum, Surfaces and Films</i> , 1988 , 6, 1736-1739	2.9	18
171	. <i>IEEE Transactions on Applied Superconductivity</i> , 1995 , 5, 1737-1740	1.8	17
170	Organometallic chemical vapor deposition of superconducting YBa ₂ Cu ₃ O ₇ films. <i>Journal of the Less Common Metals</i> , 1990 , 164-165, 444-450		17
169	de Haas-van Alphen effect in MoSi ₂ . <i>Physical Review B</i> , 1987 , 35, 7936-7938	3.3	16
168	Towards a quantitative determination of strain in Bragg Coherent X-ray Diffraction Imaging: artefacts and sign convention in reconstructions. <i>Scientific Reports</i> , 2019 , 9, 17357	4.9	15
167	New insights into single-grain mechanical behavior from temperature-dependent 3-D coherent X-ray diffraction. <i>Acta Materialia</i> , 2014 , 78, 46-55	8.4	14
166	Tungsten-niobium alloys as diffusion barriers between aluminum and silicon. <i>Journal of Vacuum Science and Technology A: Vacuum, Surfaces and Films</i> , 1988 , 6, 1650-1655	2.9	14
165	Out-of-plane stresses arising from grain interactions in textured thin films. <i>Acta Materialia</i> , 2010 , 58, 2452-2463	8.4	13
164	Impact of surface preparation on nickel-platinum alloy silicide phase formation. <i>Microelectronic Engineering</i> , 2007 , 84, 2523-2527	2.5	13
163	Stresses and interfacial structure in Au/Ni and Ag/Cu metallic multilayers. <i>Scripta Materialia</i> , 2004 , 50, 717-721	5.6	13
162	Cubic local order around Al and intermixing in short-period AlN/TiN multilayers studied by Al K-edge extended x-ray absorption fine structure spectroscopy and x-ray diffraction. <i>Applied Physics Letters</i> , 2003 , 82, 3659-3661	3.4	13

161	Reacted amorphous layers: Tantalum and niobium oxides. <i>The Philosophical Magazine: Physics of Condensed Matter B, Statistical Mechanics, Electronic, Optical and Magnetic Properties</i> , 1988 , 58, 529-538		13
160	Strain and tilt mapping in silicon around copper filled TSVs using advanced X-ray nano-diffraction. <i>Microelectronic Engineering</i> , 2015 , 137, 117-123	2.5	12
159	Investigation by High Resolution X-ray Diffraction of the local strains induced in Si by periodic arrays of oxide filled trenches. <i>Physica Status Solidi (A) Applications and Materials Science</i> , 2007 , 204, 2542-2547 ¹²	1.6	12
158	Comparison of the diffusion barrier properties of tungsten films prepared by hydrogen and silicon reduction of tungsten hexafluoride. <i>Thin Solid Films</i> , 1989 , 171, 343-357	2.2	12
157	Crystallographic orientation of facets and planar defects in functional nanostructures elucidated by nano-focused coherent diffractive X-ray imaging. <i>Nanoscale</i> , 2018 , 10, 4833-4840	7.7	11
156	In situ X-ray diffraction studies on the piezoelectric response of PZT thin films. <i>Thin Solid Films</i> , 2016 , 603, 29-33	2.2	11
155	Exploring NiBi thin-film reactions by means of simultaneous synchrotron X-Ray diffraction and substrate curvature measurements. <i>Materials Science and Engineering B: Solid-State Materials for Advanced Technology</i> , 2004 , 114-115, 67-71	3.1	11
154	Microstructural analysis of AU/NI multilayers interfaces by SAXS and STM. <i>Applied Surface Science</i> , 2002 , 188, 182-187	6.7	11
153	Preparation of YBa ₂ Cu ₃ O _{7-x} films and YBa ₂ Cu ₃ O _{7-x} /Y ₂ O ₃ multilayers using coevaporation and atomic oxygen. <i>Journal of Applied Physics</i> , 1993 , 73, 3096-3098	2.5	11
152	Texture influence on critical current density of YBCO films deposited on (100)-MgO substrates. <i>Physica C: Superconductivity and Its Applications</i> , 1994 , 235-240, 627-628	1.3	11
151	The reaction of scandium thin films with silicon: diffusion, nucleation, resistivities. <i>Applied Surface Science</i> , 1991 , 53, 138-146	6.7	11
150	Low-temperature specific heat of MoSi ₂ . <i>Physical Review B</i> , 1988 , 37, 10364-10366	3.3	11
149	Resistivity and magnetoresistance of monocrystalline TaSi ₂ and VSi ₂ . <i>Surface and Coatings Technology</i> , 1991 , 45, 237-243	4.4	10
148	Respective mobilities of metal and silicon in disilicides: Bilayers of chromium with molybdenum or tungsten. <i>Journal of Applied Physics</i> , 1990 , 67, 2410-2414	2.5	10
147	Through-silicon via-induced strain distribution in silicon interposer. <i>Applied Physics Letters</i> , 2015 , 106, 141905	3.4	9
146	An Atomistic View of the Incipient Growth of Zinc Oxide Nanolayers. <i>Crystal Growth and Design</i> , 2016 , 16, 5339-5348	3.5	9
145	Strain inhomogeneity in copper islands probed by coherent X-ray diffraction. <i>Thin Solid Films</i> , 2013 , 530, 120-124	2.2	9
144	Local strain in a 3D nano-crystal revealed by 2D coherent X-ray diffraction imaging. <i>Thin Solid Films</i> , 2007 , 515, 5557-5562	2.2	9

143	Twinning orientation in YBa ₂ Cu ₃ O _{7-x} films deposited on YAlO ₃ substrates. <i>Applied Physics Letters</i> , 1996 , 69, 1942-1944	3.4	9
142	A.c. characterization of pyrosol and C.V.D. made high T _c materials. <i>Journal of the Less Common Metals</i> , 1990 , 164-165, 1393-1399		9
141	KB scanning of X-ray beam for Laue microdiffraction on accelero-phobic samples: application to in situ mechanically loaded nanowires. <i>Journal of Synchrotron Radiation</i> , 2016 , 23, 1395-1400	2.4	9
140	In situ Bragg coherent X-ray diffraction during tensile testing of an individual Au nanowire. <i>Journal of Applied Crystallography</i> , 2018 , 51, 781-788	3.8	8
139	Silicide formation during reaction between Ni ultra-thin films and Si(001) substrates. <i>Materials Letters</i> , 2014 , 116, 139-142	3.3	8
138	Exploring PdBi(001) and PdBi(111) thin-film reactions by simultaneous synchrotron X-ray diffraction and substrate curvature measurements. <i>Thin Solid Films</i> , 2013 , 530, 100-104	2.2	8
137	In situ coherent X-ray diffraction of isolated core-shell nanowires. <i>Thin Solid Films</i> , 2013 , 530, 113-119	2.2	8
136	Piezoelectric response and electrical properties of Pb(Zr _{1-x} Ti _x)O ₃ thin films: The role of imprint and composition. <i>Journal of Applied Physics</i> , 2017 , 122, 164104	2.5	8
135	Continuous and Collective Grain Rotation in Nanoscale Thin Films during Silicidation. <i>Physical Review Letters</i> , 2015 , 115, 266101	7.4	8
134	Structure characterization of metallic multilayers by symmetric and asymmetric X-ray diffraction. <i>Thin Solid Films</i> , 1998 , 319, 78-80	2.2	8
133	Thermal expansion and stress development in the first stages of silicidation in Ti/Si thin films. <i>Journal of Applied Physics</i> , 2003 , 94, 7083-7090	2.5	8
132	Influence of segregation on the measurement of stress in thin films. <i>Journal of Applied Physics</i> , 2002 , 91, 2951-2958	2.5	8
131	The high residual resistivity of CoSi ₂ : Evidence for a homogeneity range. <i>Applied Surface Science</i> , 1989 , 38, 88-93	6.7	8
130	Experimental study of partial densities of states in MoSi ₂ . <i>Solid State Communications</i> , 1987 , 64, 129-132	1.6	8
129	Reactor for nano-focused x-ray diffraction and imaging under catalytic in situ conditions. <i>Review of Scientific Instruments</i> , 2017 , 88, 093902	1.7	7
128	Thermoelasticity and interdiffusion in CuNi multilayers. <i>Physical Review B</i> , 2012 , 85,	3.3	7
127	X-ray microbeam strain investigation on Cu ₂ Ni MEMS structures. <i>Microelectronic Engineering</i> , 2010 , 87, 394-397	2.7	7
126	Correlation between the microwave surface resistance and the volumic fraction of a-axis grains in YBa ₂ Cu ₃ O _{7-x} films. <i>Physica C: Superconductivity and Its Applications</i> , 1998 , 308, 16-20	1.3	7

125	Influence of crystallographic orientation on local strains in silicon: A combined high-resolution X-ray diffraction and finite element modelling investigation. <i>Thin Solid Films</i> , 2008 , 516, 8042-8048	2.2	7
124	X-ray scattering: A powerful probe of lattice strain in materials with small dimensions. <i>Applied Surface Science</i> , 2006 , 253, 182-187	6.7	7
123	Stress Development during the Reactive Formation of Silicide Films. <i>Defect and Diffusion Forum</i> , 2005 , 237-240, 801-812	0.7	7
122	Residual stress analysis in micro- and nano-structured materials by X-ray diffraction. <i>International Journal of Materials and Product Technology</i> , 2006 , 26, 354	1	7
121	Impact of thermal cycling on the evolution of grain, precipitate and dislocation structure in Al, 0.5% Cu, 1% Si thin films. <i>Microelectronic Engineering</i> , 2003 , 70, 447-454	2.5	7
120	Simulation of local mechanical stresses in lines on substrate. <i>Microelectronic Engineering</i> , 2003 , 70, 455-469	4.9	7
119	X-ray diffraction from inhomogeneous thin films of nanometre thickness: modelling and experiment. <i>Journal of Applied Crystallography</i> , 2003 , 36, 154-157	3.8	7
118	Pipe-diffusion ripening of Si precipitates in Al-0.5%Cu-1%Si thin films. <i>Philosophical Magazine</i> , 2005 , 85, 3541-3552	1.6	7
117	Growth and properties of MOCVD YBa ₂ Cu ₃ O _{7-x} thin films. <i>Journal of Alloys and Compounds</i> , 1993 , 195, 287-290	5.7	7
116	Measurements of critical currents as a function of temperature in YBa ₂ Cu ₃ O _{7-x} thin films: a comparative study. <i>Superconductor Science and Technology</i> , 1994 , 7, 195-205	3.1	7
115	Oxidation and formation mechanisms in disilicides: VSi ₂ and CrSi ₂ , inert marker experiments and interpretation. <i>Journal of Applied Physics</i> , 1990 , 68, 6213-6223	2.5	7
114	Stress buildup during crystallization of thin chalcogenide films for memory applications: In situ combination of synchrotron X-Ray diffraction and wafer curvature measurements. <i>Thin Solid Films</i> , 2016 , 617, 44-47	2.2	6
113	Anomalous coherent diffraction of core-shell nano-objects: A methodology for determination of composition and strain fields. <i>Physical Review B</i> , 2013 , 87,	3.3	6
112	Twinning behaviour in YBCO and PBCO thin films and in PBCO-YBCO superlattices. <i>Journal of Alloys and Compounds</i> , 1997 , 251, 322-327	5.7	6
111	Nitrogen impurity effects on nickel silicide formation at low temperatures [New Nitrogen co-plasma] approach. <i>Microelectronic Engineering</i> , 2008 , 85, 2005-2008	2.5	6
110	In-situ study of stress evolution during solid state reaction of Pd with Si(001) using synchrotron radiation. <i>Microelectronic Engineering</i> , 2003 , 70, 436-441	2.5	6
109	Investigation of local stress fields: Finite element modelling and High Resolution X-Ray Diffraction. <i>Materials Research Society Symposia Proceedings</i> , 2005 , 875, 1		6
108	Microstructure and residual stresses in (111) multilayers. <i>Thin Solid Films</i> , 1996 , 275, 29-34	2.2	6

107	Structure and morphology of YBa ₂ Cu ₃ O _{7-x} LPCVD layers. <i>Physica C: Superconductivity and Its Applications</i> , 1991 , 180, 42-45	1.3	6
106	Bilayers with chromium disilicide: Chromium-vanadium. <i>Applied Surface Science</i> , 1989 , 38, 106-116	6.7	6
105	Multispectral Spectroscopic Ellipsometry-A New Tool for In Situ Surface Analysis. <i>Materials Research Society Symposia Proceedings</i> , 1987 , 101, 403		6
104	Fast pole figure acquisition using area detectors at the DiffAbs beamline $\text{\textcircled{S}}$ Synchrotron SOLEIL. Erratum. <i>Journal of Applied Crystallography</i> , 2014 , 47, 482-482	3.8	6
103	In situ monitoring of stress change in GeTe thin films during thermal annealing and crystallization. <i>Micro and Nano Engineering</i> , 2018 , 1, 63-67	3.4	6
102	Evaluation of Alternative Atomistic Models for the Incipient Growth of ZnO by Atomic Layer Deposition. <i>Journal of Electronic Materials</i> , 2017 , 46, 3512-3517	1.9	5
101	In situ structural evolution of single particle model catalysts under ambient pressure reaction conditions. <i>Nanoscale</i> , 2018 , 11, 331-338	7.7	5
100	Multi-wavelength Bragg coherent X-ray diffraction imaging of Au particles. <i>Journal of Applied Crystallography</i> , 2020 , 53, 170-177	3.8	5
99	New insights into thermomechanical behavior of GeTe thin films during crystallization. <i>Acta Materialia</i> , 2020 , 191, 60-69	8.4	5
98	In situ combined synchrotron X-ray diffraction and wafer curvature measurements during formation of thin palladium silicide film on Si(001) and Si (111). <i>Nuclear Instruments & Methods in Physics Research B</i> , 2012 , 284, 74-77	1.2	5
97	First stage of CoSi ₂ formation during a solid-state reaction. <i>Journal of Applied Physics</i> , 2014 , 116, 245301-5	1.5	5
96	3D strain imaging in sub-micrometer crystals using cross-reciprocal space measurements: Numerical feasibility and experimental methodology. <i>Nuclear Instruments & Methods in Physics Research B</i> , 2010 , 268, 388-393	1.2	5
95	Self-aligned nickel-platinum silicide oxidation. <i>Materials Science and Engineering B: Solid-State Materials for Advanced Technology</i> , 2008 , 154-155, 155-158	3.1	5
94	Stresses in Copper Damascene Lines: In-situ Measurements and Finite Element Analysis. <i>AIP Conference Proceedings</i> , 2006 ,	0	5
93	Diffraction from Periodic Arrays of Oxide-Filled Trenches in Silicon: Investigation of Local Strains. <i>Materials Research Society Symposia Proceedings</i> , 2006 , 913, 1		5
92	Numerical modeling of stress build up during nickel silicidation under anisothermal annealing. <i>Materials Science and Engineering B: Solid-State Materials for Advanced Technology</i> , 2006 , 135, 95-102	3.1	5
91	Chemically diffuse interface in (1 1 1) Au ₂ Ni multilayers: an anomalous X-ray diffraction analysis. <i>Applied Surface Science</i> , 2002 , 188, 110-114	6.7	5
90	High Quality YBa ₂ Cu ₃ O _{7-x} Superconducting Thin Films Grown by MOCVD. <i>European Physical Journal Special Topics</i> , 1995 , 05, C5-365-C5-371		5

89	Diffusion of dopants in tungsten disilicide: effects of diffusion paths. <i>Applied Surface Science</i> , 1991 , 53, 165-170	6.7	5
88	Dopant diffusion in silicides: Effect of diffusion paths. <i>Journal of Vacuum Science and Technology A: Vacuum, Surfaces and Films</i> , 1992 , 10, 907-911	2.9	5
87	Magnetic and transmission electron microscopy studies of the formation of cobalt silicide thin films. <i>Journal of Applied Physics</i> , 1988 , 64, 3014-3017	2.5	5
86	In situ measurements of the structure and strain of a π -conjugated semiconducting polymer under mechanical load. <i>Journal of Applied Physics</i> , 2020 , 127, 045108	2.5	4
85	Combined coherent x-ray micro-diffraction and local mechanical loading on copper nanocrystals. <i>Journal of Physics: Conference Series</i> , 2013 , 425, 132003	0.3	4
84	Lattice instabilities in hexagonal NiSi: A NiAs prototype structure. <i>Physical Review B</i> , 2010 , 81,	3.3	4
83	Post Si(C)N hillock nucleation and growth in IC copper lines controlled by diffusional creep. <i>Microelectronic Engineering</i> , 2010 , 87, 361-364	2.5	4
82	Finite element simulations of coherent diffraction in elastoplastic polycrystalline aggregates. <i>Comptes Rendus Physique</i> , 2010 , 11, 293-303	1.4	4
81	Stress in Ag/Ni Multilayers: A Comparison of Specimen-Curvature and X-Ray Diffraction Methods. <i>Materials Research Society Symposia Proceedings</i> , 1997 , 472, 299		4
80	Residual Stresses in Ultrathin Metal Sublayers Within Au/Ni Multilayers. <i>Materials Research Society Symposia Proceedings</i> , 1997 , 475, 363		4
79	Diffraction analysis of elastic strains in micro and nanostructures. <i>Zeitschrift für Kristallographie</i> , 2008 , 223, 569-574		4
78	Texture and strain in narrow copper damascene interconnect lines: An X-ray diffraction analysis. <i>Microelectronic Engineering</i> , 2008 , 85, 2175-2178	2.5	4
77	In situ stress measurements during the growth at different temperatures of Ag/Cu(111) multilayers. <i>Journal of Applied Physics</i> , 2004 , 95, 1152-1161	2.5	4
76	First stages of silicidation in Ti/Si thin films. <i>Microelectronic Engineering</i> , 2003 , 70, 166-173	2.5	4
75	Transport and Low Temperature Specific Heat Measurements of CrSi ₂ Single Crystals. <i>Materials Research Society Symposia Proceedings</i> , 1995 , 402, 343		4
74	Some properties of Cr _x V _{1-x} Si ₂ and Cr _x Mo _{1-x} Si ₂ thin films. <i>Applied Surface Science</i> , 1989 , 38, 94-105	6.7	4
73	Mapping Inversion Domain Boundaries along Single GaN Wires with Bragg Coherent X-ray Imaging. <i>ACS Nano</i> , 2020 , 14, 10305-10312	16.7	4
72	Continuous scanning for Bragg coherent X-ray imaging. <i>Scientific Reports</i> , 2020 , 10, 12760	4.9	4

71	Facet-Dependent Strain Determination in Electrochemically Synthesized Platinum Model Catalytic Nanoparticles. <i>Small</i> , 2021 , 17, e2007702	11	4
70	In Situ Coherent X-ray Diffraction during Three-Point Bending of a Au Nanowire: Visualization and Quantification. <i>Quantum Beam Science</i> , 2018 , 2, 24	1.6	4
69	Three-point bending behavior of a Au nanowire studied by in-situ Laue micro-diffraction. <i>Journal of Applied Physics</i> , 2018 , 124, 185104	2.5	4
68	Local strain induced in silicon by Si ₃ N ₄ lines: Modeling and experimental investigation via X-ray diffraction. <i>Nuclear Instruments & Methods in Physics Research B</i> , 2012 , 284, 23-28	1.2	3
67	YBCO films deposited on YAlO ₃ /sub 3/ substrates: microstructure and transport properties. <i>IEEE Transactions on Applied Superconductivity</i> , 1997 , 7, 1268-1271	1.8	3
66	Transport critical current in MOCVD YBa ₂ Cu ₃ O ₇ thin films using a pulse technique. <i>Journal of Alloys and Compounds</i> , 1993 , 195, 475-478	5.7	3
65	Comparative study of the irreversibility line and of harmonic generation in field modulated microwave absorption on YBa ₂ Cu ₃ O ₇ thin films. <i>Journal of Alloys and Compounds</i> , 1993 , 195, 587-590	5.7	3
64	Irreversibility line of YBa ₂ Cu ₃ O ₇ thin films studied by field modulated microwave absorption. <i>Physica C: Superconductivity and Its Applications</i> , 1994 , 235-240, 3153-3154	1.3	3
63	Low temperature specific heat of CoSi ₂ . <i>Applied Surface Science</i> , 1991 , 53, 240-242	6.7	3
62	Diffusion of elements implanted in amorphous titanium disilicide. <i>Applied Surface Science</i> , 1993 , 73, 167-174	6.7	3
61	Decreasing reaction rate at the end of silicidation: In-situ CoSi ₂ XRD study and modeling. <i>Microelectronic Engineering</i> , 2013 , 106, 125-128	2.5	2
60	Comparative study of metallic silicide-germanide orthorhombic MnP systems. <i>Journal of Physics Condensed Matter</i> , 2013 , 25, 355403	1.8	2
59	Thermo-mechanical study of a 2.5D passive silicon interposer technology: Experimental, numerical and In-Situ stress sensors developments 2013 ,		2
58	Relation between strain and composition in coherent epitaxial Cu/Ni multilayers: Influence of strong concentration gradients. <i>Physical Review B</i> , 2009 , 79,	3.3	2
57	Structural and magnetic properties of Ni/Cr multilayers. <i>Journal of Magnetism and Magnetic Materials</i> , 1997 , 165, 205-207	2.8	2
56	Comparison between different X-ray diffraction methods to extract strains in metallic multilayers. <i>Nuovo Cimento Della Societa Italiana Di Fisica D - Condensed Matter, Atomic, Molecular and Chemical Physics, Biophysics</i> , 1997 , 19, 577-583		2
55	The composition analysis of YBa ₂ Cu ₃ O _{7-x} and PrBa ₂ Cu ₃ O _{7-x} thin films and (YBa ₂ Cu ₃ O _{7-x} /PrBa ₂ Cu ₃ O _{7-x}) _n heterostructures prepared by CVD. <i>Fresenius Journal of Analytical Chemistry</i> , 1997 , 357, 1061-1065		2
54	Local strains induced in silicon channel by a periodic array of nitride capped poly lines investigated by high resolution X-ray diffraction. <i>Materials Science and Engineering B: Solid-State Materials for Advanced Technology</i> , 2008 , 154-155, 129-132	3.1	2

53	In situ study of strain evolution during thin film Ti/Al(Si,Cu) reaction using synchrotron radiation. <i>Microelectronic Engineering</i> , 2002 , 64, 81-89	2.5	2
52	Stress Development and Relaxation during Reaction of a Cobalt Film with a Silicon Substrate. <i>Defect and Diffusion Forum</i> , 2005 , 237-240, 518-523	0.7	2
51	Growth of YBa ₂ Cu ₃ O _{7-x} / PrBa ₂ Cu ₃ O _{7-x} heterostructures by chemical vapor deposition. <i>Physica C: Superconductivity and Its Applications</i> , 1994 , 235-240, 723-724	1.3	2
50	Low temperature specific heat measurements of VSi ₂ , NbSi ₂ and TaSi ₂ . <i>Applied Surface Science</i> , 1993 , 73, 232-236	6.7	2
49	Growth of (YBaCuO) _m /(PrBaCuO) _n Superlattices by MOCVD. <i>European Physical Journal Special Topics</i> , 1995 , 05, C5-423-C5-430		2
48	Crystallization behavior of N -doped Ge-rich GST thin films and nanostructures: An in-situ synchrotron X-ray diffraction study. <i>Microelectronic Engineering</i> , 2021 , 111573	2.5	2
47	Berkovich nanoindentation study of 16 nm Cu/Nb ARB nanolaminate: Effect of anisotropy on the surface pileup. <i>MRS Advances</i> , 2021 , 6, 495-499	0.7	2
46	Twin boundary migration in an individual platinum nanocrystal during catalytic CO oxidation. <i>Nature Communications</i> , 2021 , 12, 5385	17.4	2
45	A Complex Interrelationship between Temperature-Dependent Polyquaterthiophene (PQT) Structural and Electrical Properties. <i>Journal of Physical Chemistry C</i> , 2017 , 121, 23149-23157	3.8	1
44	Plastic behaviour and deformation mechanisms in silicon nano-objects. <i>Journal of Physics: Conference Series</i> , 2019 , 1190, 012004	0.3	1
43	Temperature dependency of the strain distribution induced by TSVs in silicon: A comparative study between micro-Laue and monochromatic nano-diffraction. <i>Microelectronic Engineering</i> , 2016 , 156, 59-64	2.5	1
42	CoSi ₂ ultra-thin layer formation kinetics and texture from X-ray diffraction. <i>Thin Solid Films</i> , 2013 , 541, 17-20	2.2	1
41	In situ coupling of atomic force microscopy and sub-micrometer focused X-ray techniques. <i>Materials Research Society Symposia Proceedings</i> , 2014 , 1712, 63		1
40	Nanometer scale assessment of mechanical strain induced in silicon by a periodic line array. <i>Journal of Nanoscience and Nanotechnology</i> , 2011 , 11, 9160-6	1.3	1
39	High-resolution X-ray diffraction as a tool to investigate the evolution of local stress in sub-micrometric Si lines isolated by periodic arrays of oxide-filled trenches. <i>Materials Science in Semiconductor Processing</i> , 2009 , 12, 64-70	4.3	1
38	Investigating Interdiffusion in Mo/V Multilayers from X-Ray Scattering and Kinetic Simulations. <i>Defect and Diffusion Forum</i> , 2007 , 264, 13-18	0.7	1
37	Stresses and Interfacial Structure in Metal Films and Multilayers of Nanometre Thickness. <i>Journal of Metastable and Nanocrystalline Materials</i> , 2004 , 19, 129-152	0.2	1
36	Stresses in Multilayer Systems: Test of the sin ² ψ Method. <i>Advanced Engineering Materials</i> , 2002 , 4, 557-561	1.5	1

35	In Situ Stress and Strain Measurements During the Growth of Cu/Ni (001) Multilayers. <i>Materials Research Society Symposia Proceedings</i> , 2000 , 615, 861		1
34	Stress evolution in a Ti/Al(Si,Cu) dual layer during annealing. <i>Materials Research Society Symposia Proceedings</i> , 2001 , 673, 1		1
33	X-Ray Diffraction Analysis and Modeling of Strain Induced Thermal Cycling in a Thin Aluminum (011) Bicrystal Film. <i>Materials Research Society Symposia Proceedings</i> , 2001 , 695, 1		1
32	Internal Stress In Sputtered Silver Nickel Thin Films And Multilayers: Sputtering Pressure And Thickness Effects. <i>Materials Research Society Symposia Proceedings</i> , 1999 , 562, 123		1
31	Angular dependence of the magnetoresistance of TiSi ₂ single crystals. <i>Applied Surface Science</i> , 1995 , 91, 98-102	6.7	1
30	Influence of the microstructure on the residual strains in (111) Au/Ni multilayers. <i>Journal of Magnetism and Magnetic Materials</i> , 1996 , 156, 31-32	2.8	1
29	Field modulated microwave absorption in YBa ₂ Cu ₃ O ₇ /PrBa ₂ Cu ₃ O ₇ multilayers. <i>Journal of Low Temperature Physics</i> , 1996 , 105, 1061-1066	1.3	1
28	Precursor Delivery for the Deposition of Superconducting Oxides: a Comparison Between Solid Sources and Aerosol. <i>Materials Research Society Symposia Proceedings</i> , 1993 , 335, 209		1
27	Thermal modelization and experiments on the current of superconducting microbridges dependence to light in the 1000K range. <i>Physica B: Condensed Matter</i> , 1994 , 194-196, 2125-2126	2.8	1
26	Transmission electron microscopy studies of thin films of YBa ₂ Cu ₃ O _{7-x} . <i>Physica C: Superconductivity and Its Applications</i> , 1994 , 235-240, 655-656	1.3	1
25	Superconducting properties of YBa ₂ Cu ₃ O ₇ films deposited by chemical vapor deposition. <i>Physica C: Superconductivity and Its Applications</i> , 1991 , 185-189, 2113-2114	1.3	1
24	In-Situ Preparation of Y-Ba-Cu-O Thin Films Using Mass-Spectrometer Rate Control and Atomic Oxygen. <i>Materials Research Society Symposia Proceedings</i> , 1992 , 275, 299		1
23	Fundamental and harmonic a.c. susceptibility response of MOCVD YBa ₂ Cu ₃ O ₇ thin films: Model of flux line behaviour. <i>Cryogenics</i> , 1993 , 33, 497-501	1.8	1
22	Ion-implantation-induced fluorine agglomeration in tungsten disilicide prepared by low-pressure chemical vapour deposition. <i>Nuclear Instruments & Methods in Physics Research B</i> , 1989 , 40-41, 595-598	1.2	1
21	First stages of plasticity in three-point bent Au nanowires detected by in situ Laue microdiffraction. <i>Applied Physics Letters</i> , 2020 , 116, 243101	3.4	1
20	Piezoelectric Properties of PbLa(ZrTi)O Thin Films Studied by In Situ X-ray Diffraction. <i>Materials</i> , 2020 , 13,	3.5	1
19	Energy-dispersive X-ray micro Laue diffraction on a bent gold nanowire. <i>Journal of Applied Crystallography</i> , 2021 , 54, 80-86	3.8	1
18	Thermo-mechanical characterization of passive stress sensors in Si interposer. <i>Microelectronics Reliability</i> , 2015 , 55, 738-746	1.2	0

17	Variable-Wavelength Quick Scanning Nanofocused X-Ray Microscopy for In Situ Strain and Tilt Mapping. <i>Small</i> , 2020 , 16, e1905990	11	○
16	Simultaneous Multi-Bragg Peak Coherent X-ray Diffraction Imaging. <i>Crystals</i> , 2021 , 11, 312	2.3	○
15	In depth characterization of Ge-Si core-shell nanowires using X-ray coherent diffraction and time resolved pump-probe spectroscopy. <i>Journal of Applied Physics</i> , 2019 , 126, 204304	2.5	○
14	In-situ force measurement during nano-indentation combined with Laue microdiffraction. <i>Nano Select</i> , 2021 , 2, 99-106	3.1	○
13	Strain Distribution Induced in SOI Photonic Substrate by Through Silicon via Using Advanced Scanning X-Ray Nano-Diffraction. <i>IEEE Transactions on Device and Materials Reliability</i> , 2018 , 18, 529-533 ^{1.6}		○
12	When More Is Less: Plastic Weakening of Single Crystalline Ag Nanoparticles by the Polycrystalline Au Shell. <i>ACS Nano</i> , 2021 , 15, 14061-14070	16.7	○
11	Time-resolved piezoelectric response in relaxor ferroelectric (Pb _{0.88} La _{0.12})(Zr _{0.52} Ti _{0.48})O ₃ thin films. <i>Journal of Applied Physics</i> , 2022 , 131, 064102	2.5	○
10	X-ray nanodiffraction in forward scattering and Bragg geometry of a single isolated Ag/Au nanowire. <i>Thin Solid Films</i> , 2016 , 617, 9-13	2.2	
9	Simulation et détermination par rayons X des contraintes dans des micro-composants modèles. <i>European Physical Journal Special Topics</i> , 2004 , 118, 109-115		
8	X-ray scattering: A wonderful tool to probe lattice strains in materials with small dimensions. <i>Materials Research Society Symposia Proceedings</i> , 2004 , 840, Q3.2.1		
7	The early stages of stress development during epitaxial growth of Ag/Cu multilayers. <i>Materials Research Society Symposia Proceedings</i> , 2003 , 791, 1		
6	In Situ Curvature and Diffraction Studies of Pd Films on Si(001) During Solid-State Reaction. <i>Materials Research Society Symposia Proceedings</i> , 2000 , 615, 831		
5	Interdependence between strain relaxation and segregation in Au/Ni multilayers. <i>Journal of Magnetism and Magnetic Materials</i> , 1999 , 198-199, 593-595	2.8	
4	An In-Situ Study of the Segregation and the Strain Relaxation During Growth of Gold and Nickel Ultrathin Films. <i>Materials Research Society Symposia Proceedings</i> , 1999 , 562, 189		
3	Magnetic properties of superconducting YBa ₂ Cu ₃ O _{7-x} CVD thin films 1992 , 79-84		
2	X-Ray Diffraction Analysis of Elastic Strains at the Nanoscale 233-258		
1	Plasticity in inhomogeneously strained Au nanowires studied by Laue microdiffraction. <i>MRS Advances</i> , 2018 , 3, 2331-2339	0.7	